

L10: Analog Building Blocks

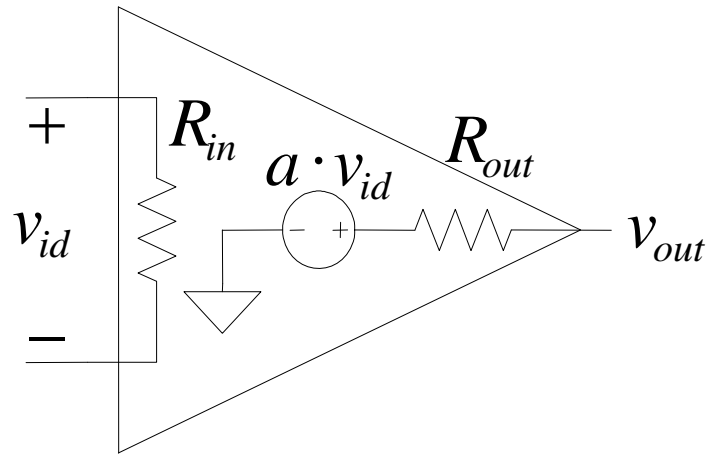
(OpAmps, A/D, D/A)



Acknowledgement: Dave Wentzloff

Lecture Notes prepared by Professor Anantha Chadrakasan

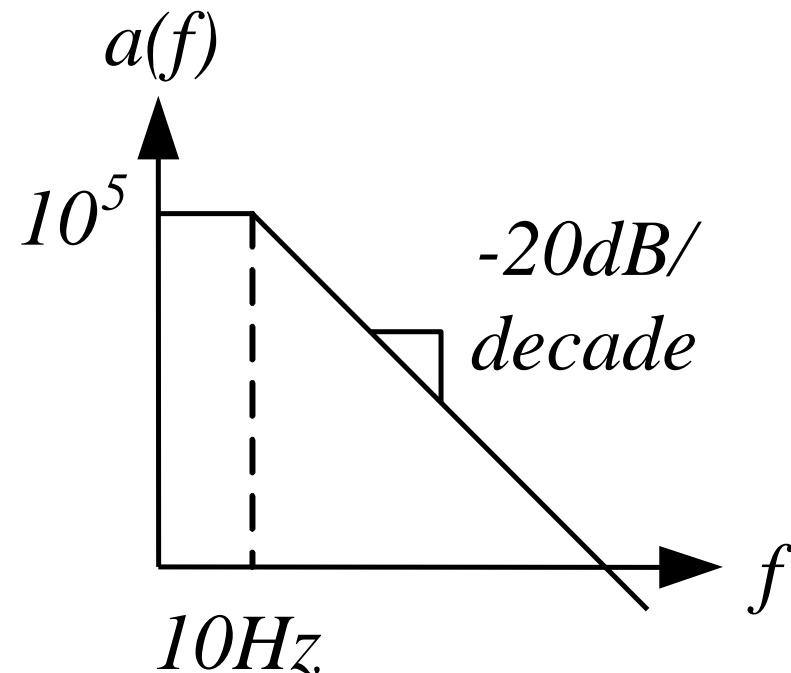
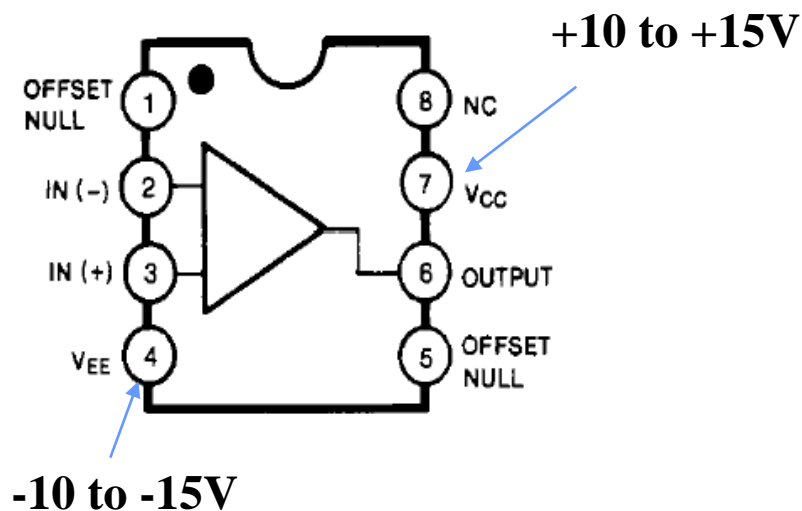
DC Model

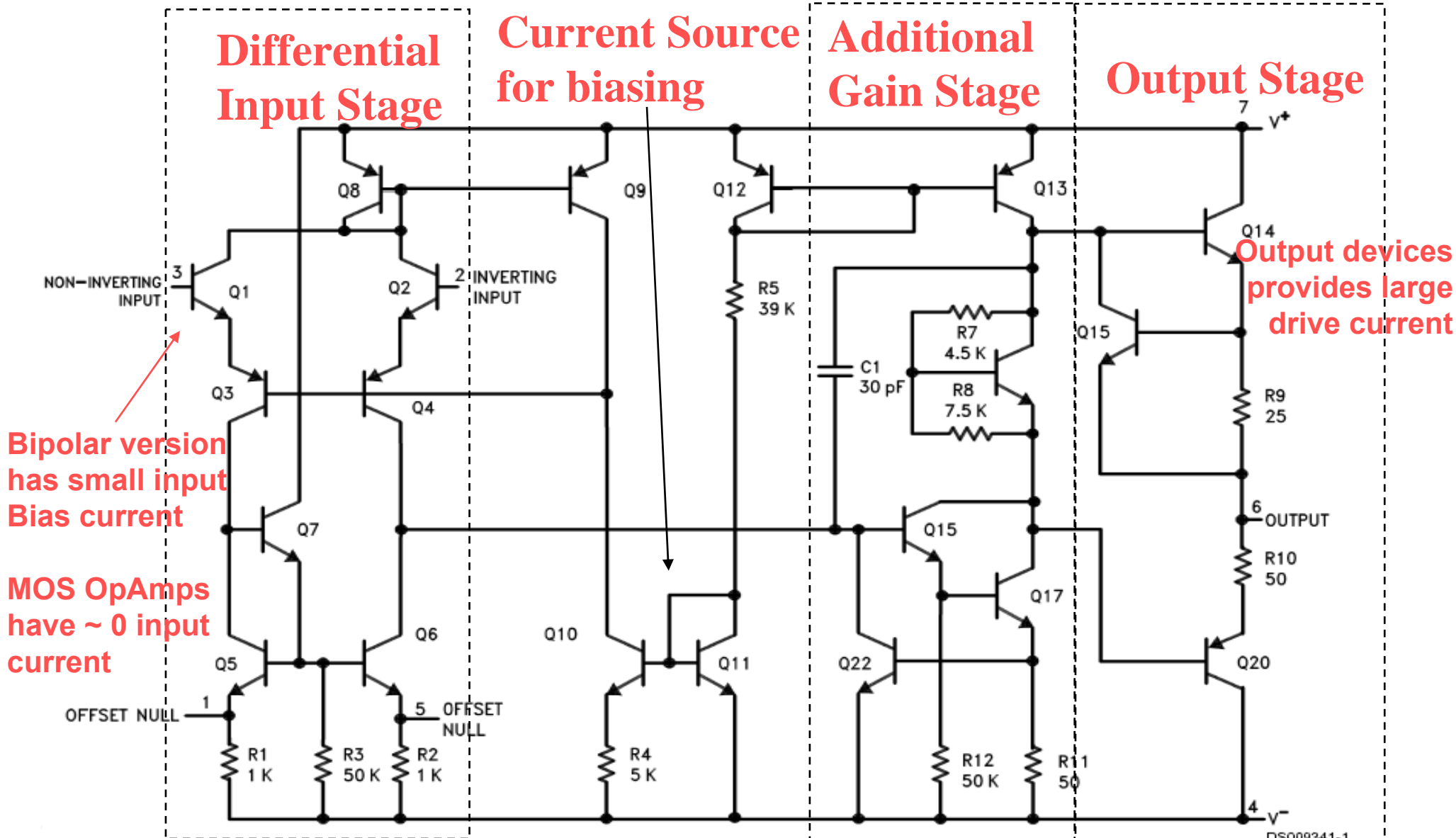


- Typically very high input resistance $\sim 300\text{K}\Omega$
- High DC gain ($\sim 10^5$)
- Output resistance $\sim 75\Omega$

$$V_{out} = a(f) \cdot V_{in}$$

LM741 Pinout



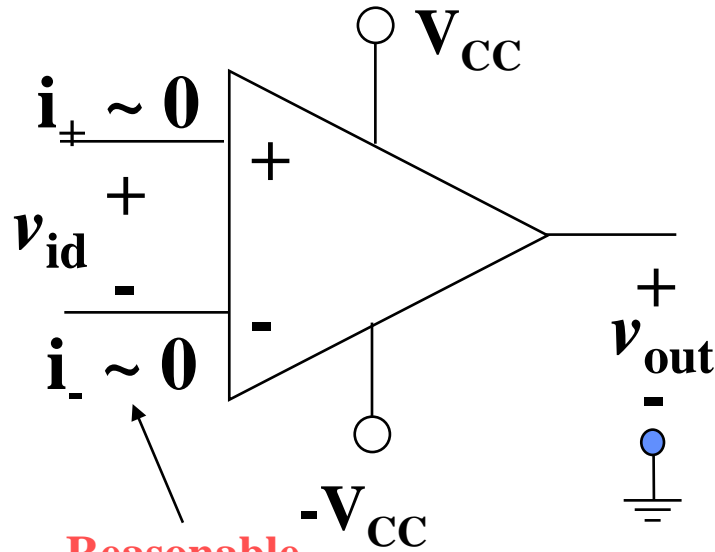


Bipolar version has small input Bias current

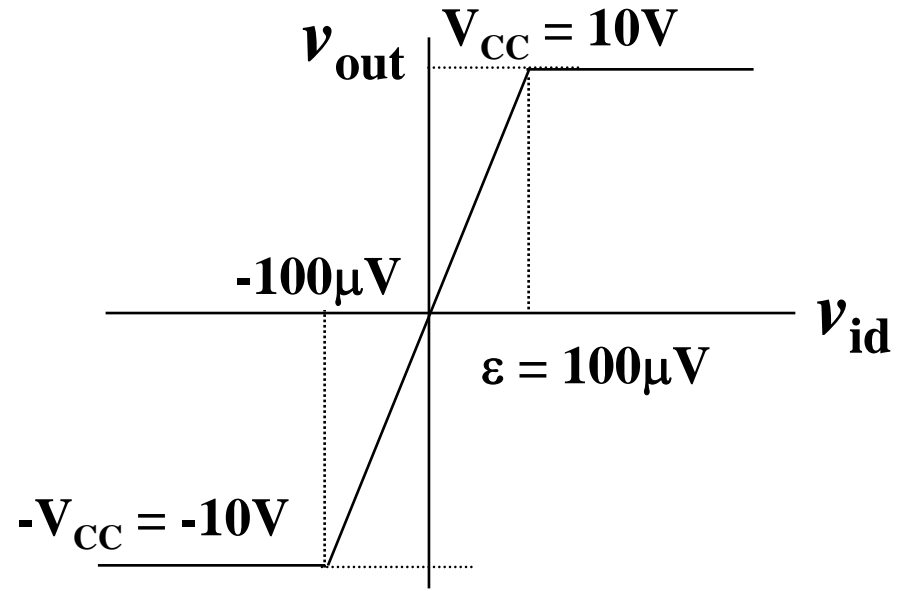
MOS OpAmps have ~ 0 input current

Output devices provides large drive current

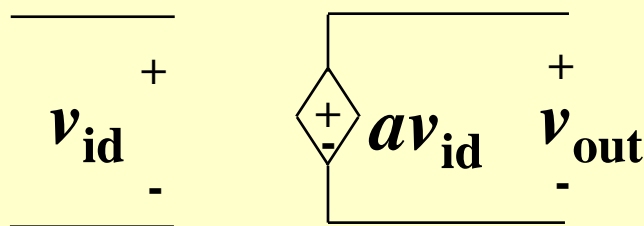
Gain is Sensitive to Operating Condition (e.g., Device, Temperature, Power supply voltage, etc.)



Reasonable approximation

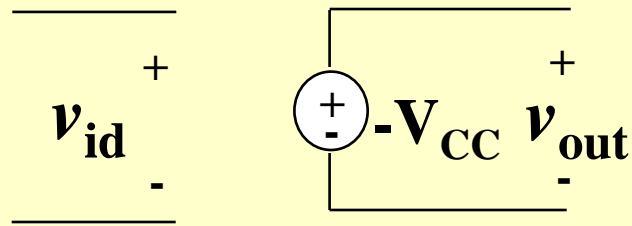


Linear Mode



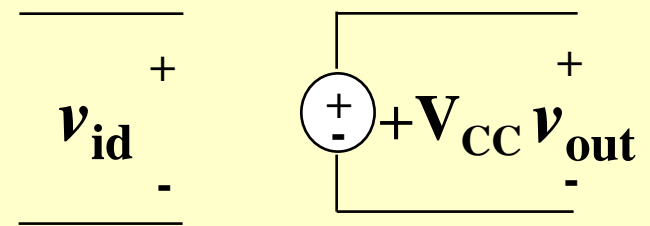
If $-V_{CC} < v_{out} < V_{CC}$

Negative Saturation



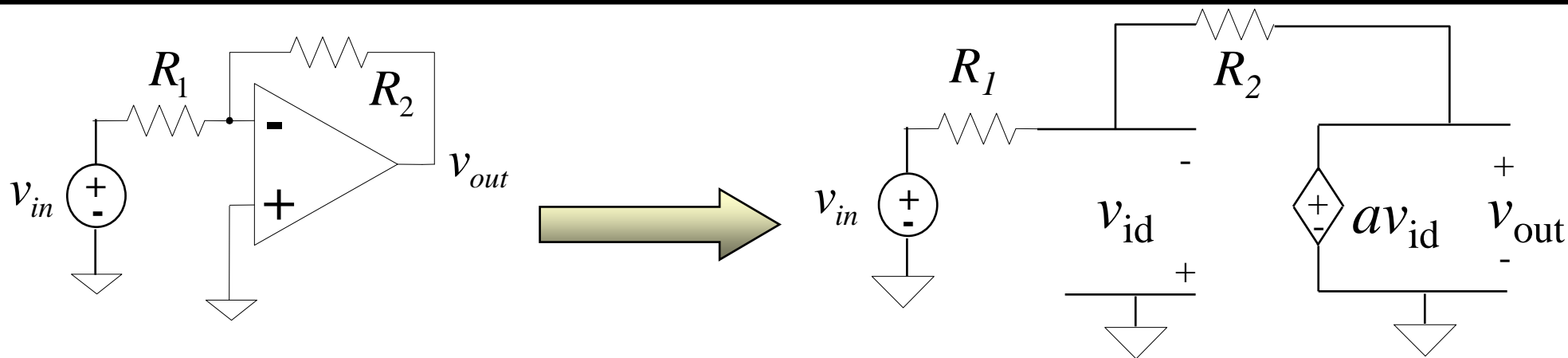
$v_{id} < -\epsilon$

Positive Saturation



$v_{id} > \epsilon$

Small input range for "Open" loop Configuration

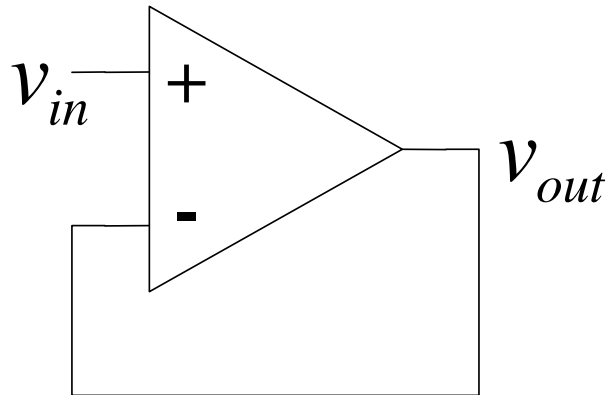


$$\frac{v_{in} + v_{id}}{R_1} + \frac{v_{out} + v_{id}}{R_2} = 0 \quad v_{id} = \frac{v_{out}}{a} \quad \frac{v_{in}}{R_1} = -\frac{v_{out}}{a} \left[\frac{1}{R_1} + \frac{a}{R_2} + \frac{1}{R_2} \right]$$

$$\frac{v_{out}}{v_{in}} = -\frac{R_2 a}{(1+a)R_1 + R_2} \approx -\frac{R_2}{R_1} \text{ (if } a \gg 1)$$

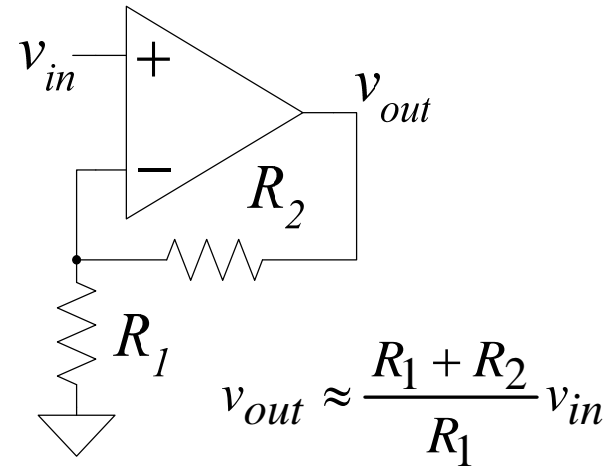
- Overall (closed loop) gain does not depend on open loop gain
- Trade gain for robustness
- Easier analysis approach: “virtual short circuit approach”
 - $v_+ = v_- = 0$ if OpAmp is linear

Voltage Follower (buffer)



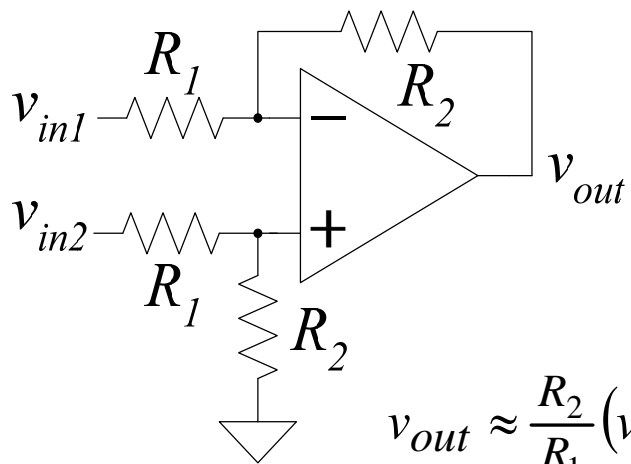
$$v_{out} \approx v_{in}$$

Non-inverting



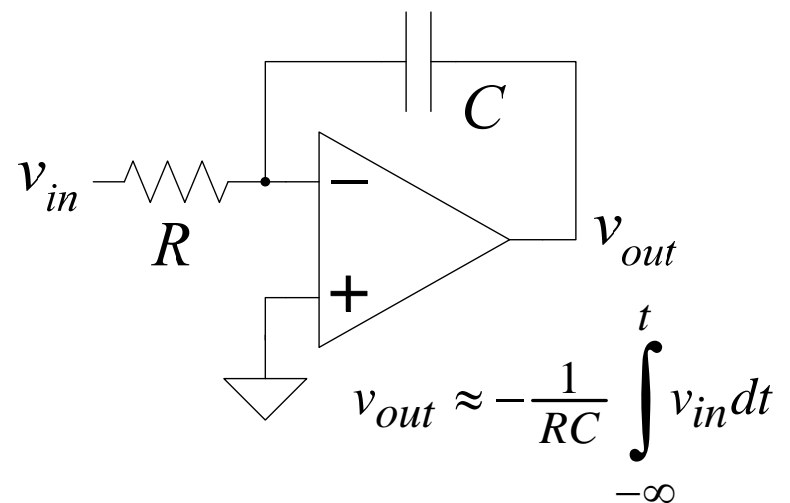
$$v_{out} \approx \frac{R_1 + R_2}{R_1} v_{in}$$

Differential Input



$$v_{out} \approx \frac{R_2}{R_1} (v_{in2} - v_{in1})$$

Integrator



$$v_{out} \approx -\frac{1}{RC} \int_{-\infty}^t v_{in} dt$$

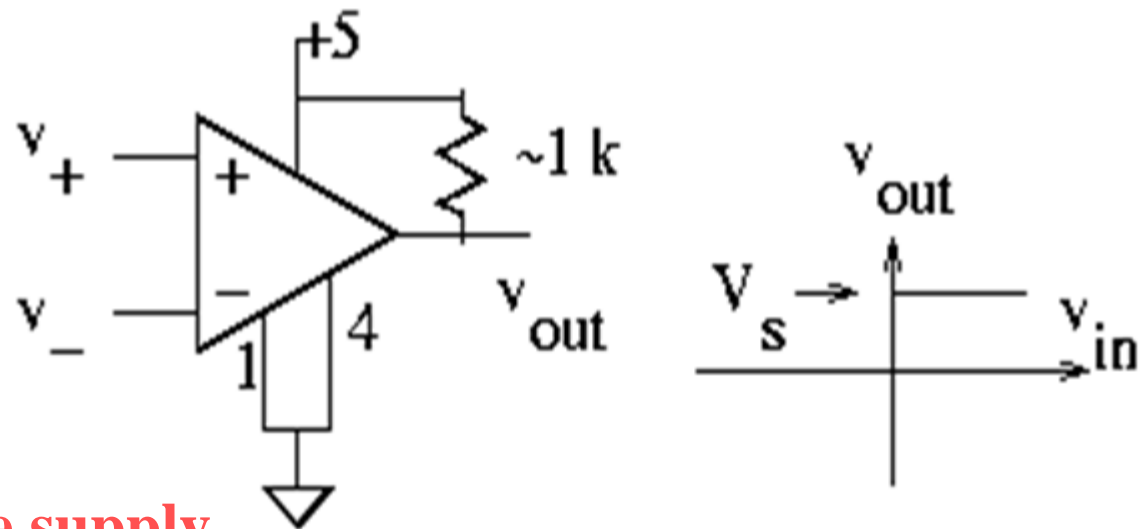
Analog Comparator:

Is $V_+ > V_-$?

The Output is a **DIGITAL** signal

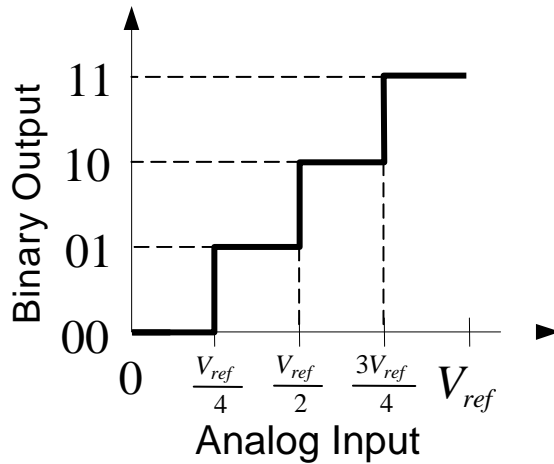
Analog Comparator: Analog to TTL

LM 311 Needs Pull-Up

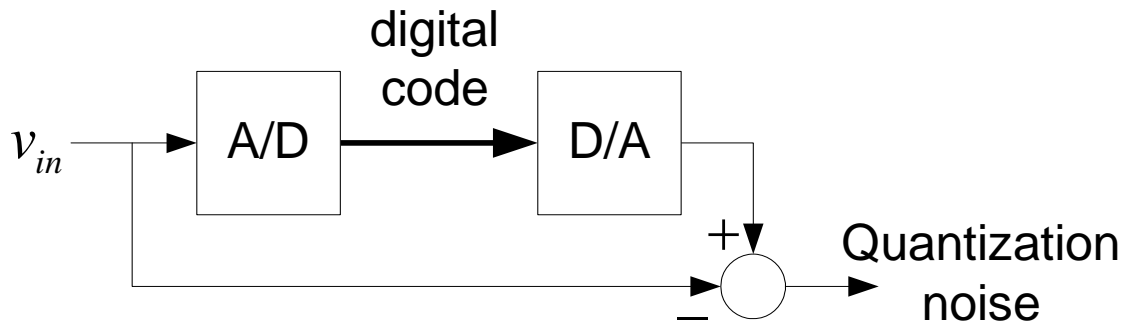
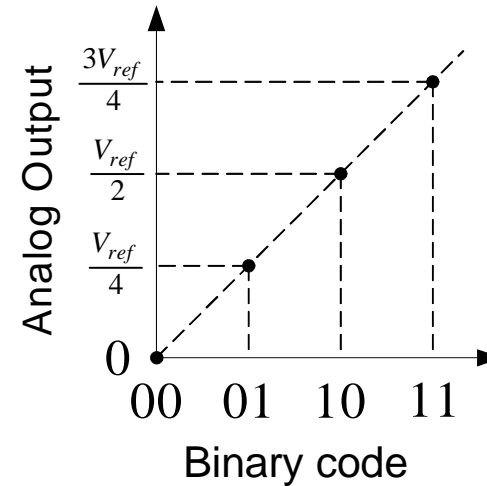


LM311 is a single supply comparator

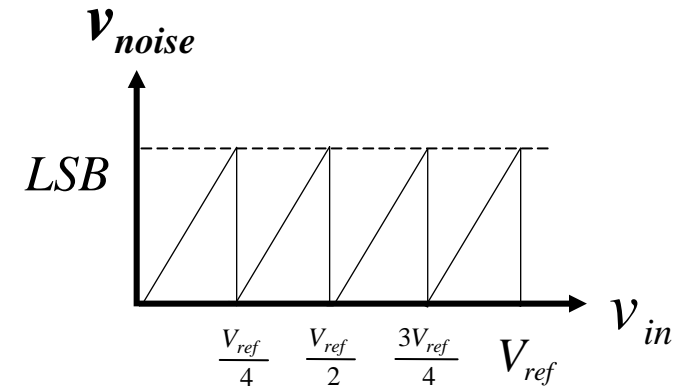
A/D Conversion



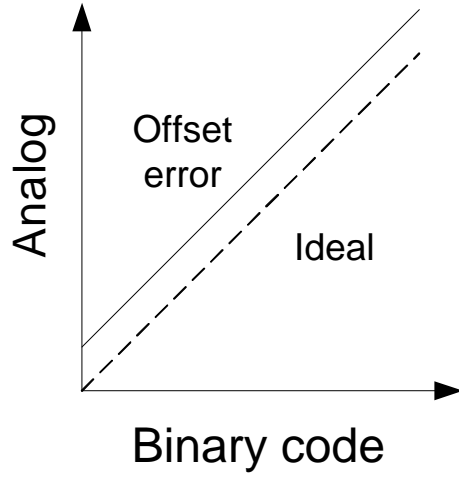
D/A Conversion



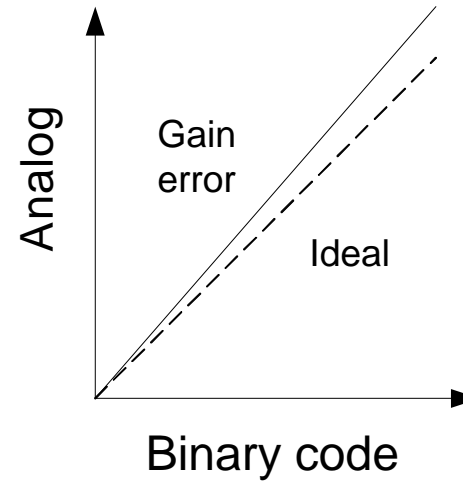
- Quantization noise exists even with *ideal* A/D and D/A converters



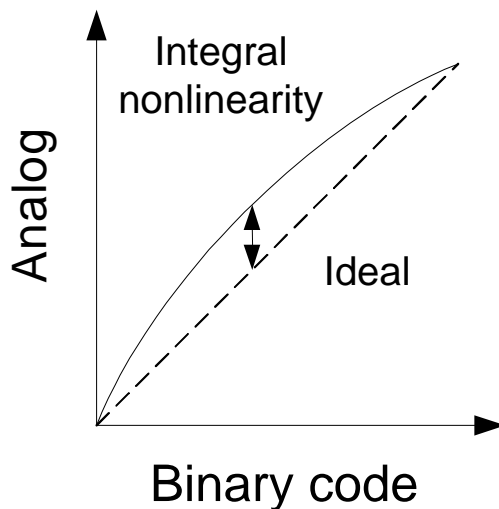
Offset – a constant voltage offset that appears at the output when the digital input is 0



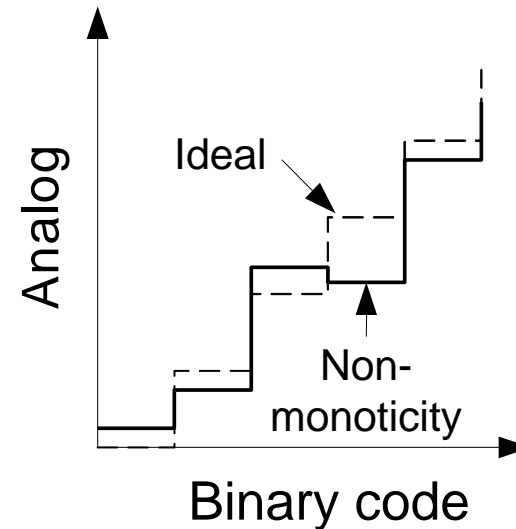
Gain error – deviation of slope from ideal value of 1

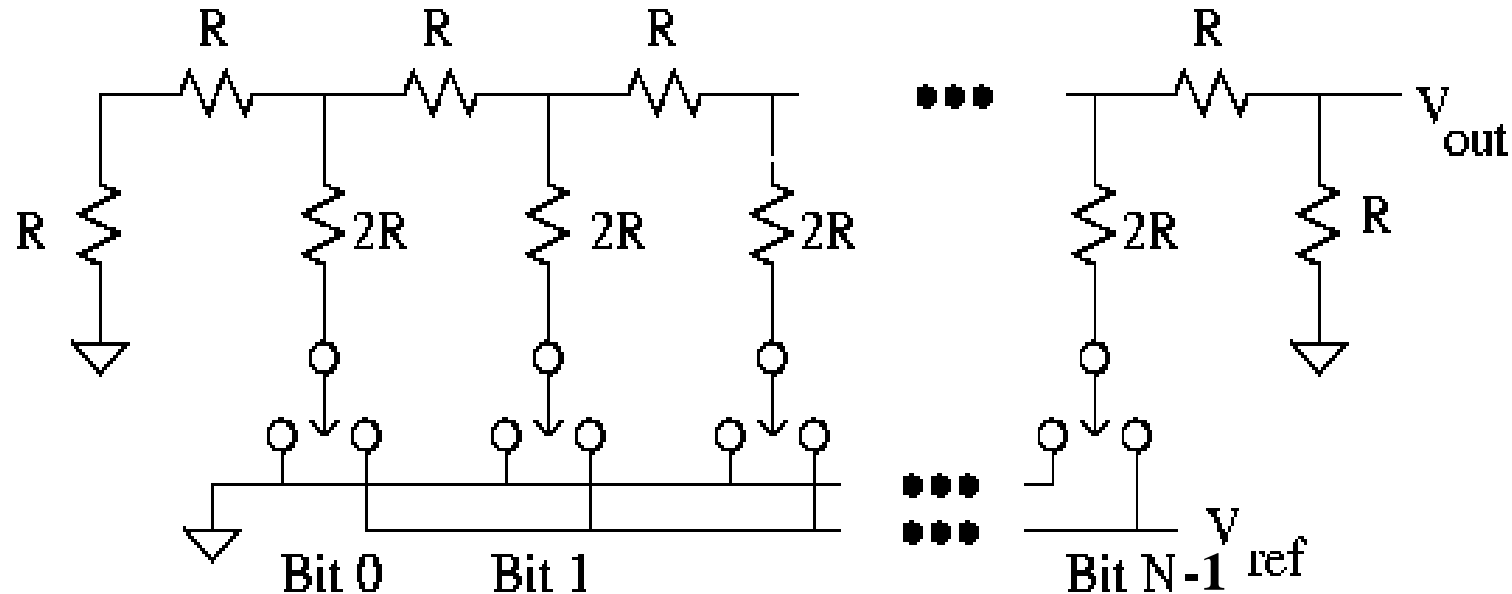


Integral Nonlinearity – maximum deviation from the ideal analog output voltage



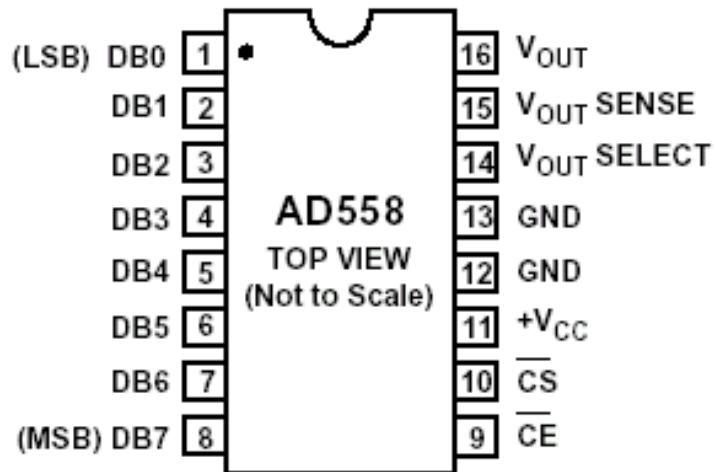
Differential nonlinearity – the largest increment in analog output for a 1-bit change





$$V_{\text{out}} = \frac{1}{6} V_{\text{ref}} \left[B_7 + \frac{1}{2} B_6 + \frac{1}{4} B_5 + \dots + \frac{1}{128} B_0 \right]$$

- Note that the driving point impedance (resistance) is the same for each cell.
- R-2R Ladder achieves large current division ratios with only two resistor values



Input Logic Coding

Digital Input Code			Output Voltage	
Binary	Hexadecimal	Decimal	2.56 V Range	10.000 V Range
0000 0000	00	0	0	0
0000 0001	01	1	0.010 V	0.039 V
0000 0010	02	2	0.020 V	0.078 V
0000 1111	0F	15	0.150 V	0.586 V
0001 0000	10	16	0.160 V	0.625 V
0111 1111	7F	127	1.270 V	4.961 V
1000 0000	80	128	1.280 V	5.000 V
1100 0000	C0	192	1.920 V	7.500 V
1111 1111	FF	255	2.55 V	9.961 V

- **8-bit DAC**
- **Single Supply Operation: 5V to 15V**
- **Integrates required references (bandgap voltage reference)**
- **Uses a R-2R resistor ladder**
- **Settling time 1 μ s**
- **Programmable output range from 0V to 2.56V or 0V to 10V**
- **Simple Latch based interface**

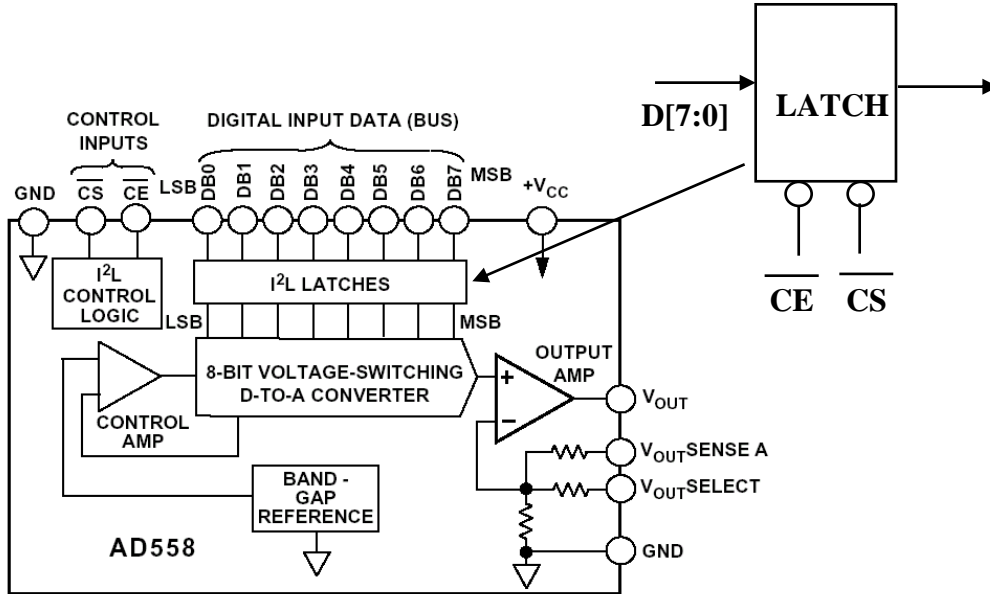


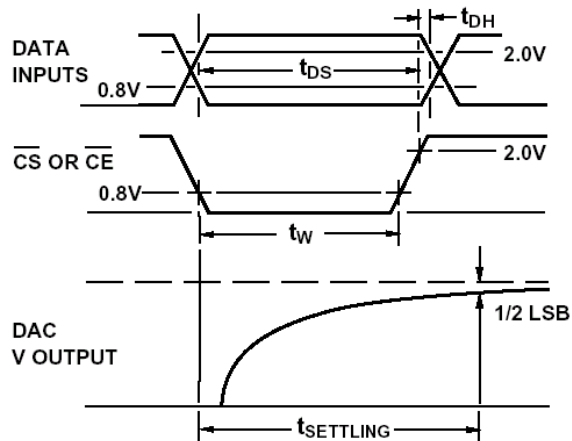
Table I. AD558 Control Logic Truth Table

Input Data	\overline{CE}	\overline{CS}	DAC Data	Latch Condition
0	0	0	0	“Transparent”
1	0	0	1	“Transparent”
0	g	0	0	Latching
1	g	0	1	Latching
0	0	g	0	Latching
1	0	g	1	Latching
X	1	X	Previous Data	Latched
X	X	1	Previous Data	Latched

NOTES

X = Does not matter.

g = Logic Threshold at Positive-Going Transition.



- t_w = STORAGE PULSE WIDTH = 200ns MIN
- t_{DH} = DATA HOLD TIME = 10ns MIN
- t_{DS} = DATA SETUP TIME = 200ns MIN
- $t_{SETTLING}$ = DAC OUTPUT SETTLING TIME TO $\pm 1/2$ LSB

Outputs are noisy when input bits settles, so it is best to have inputs stable before latching the input data

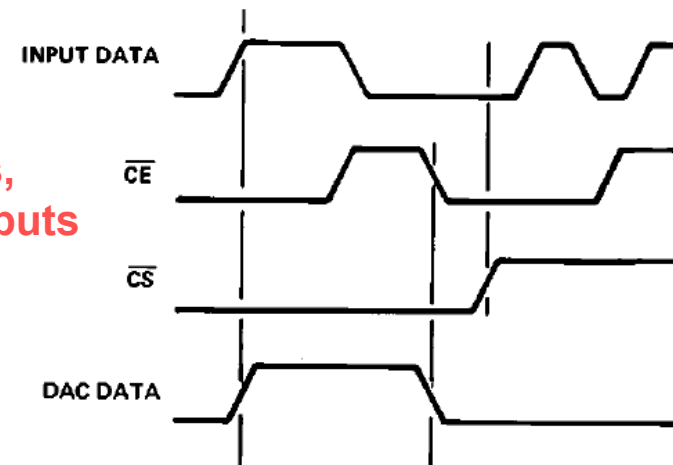
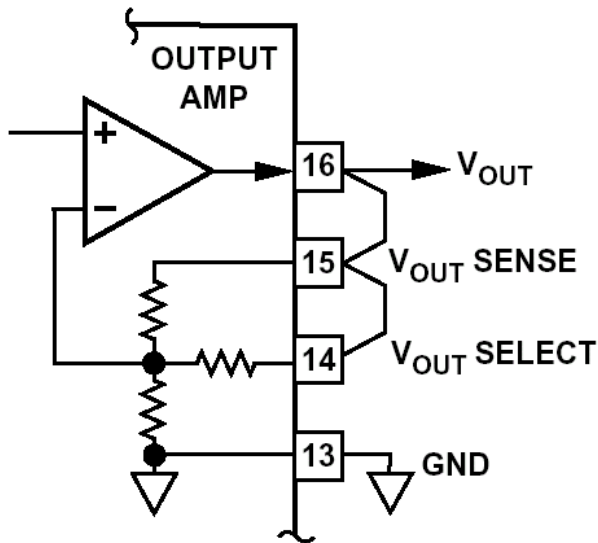
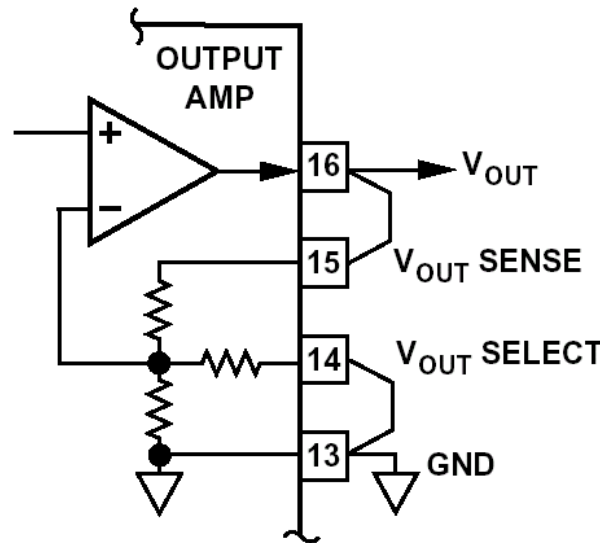


Figure 6. AD558 Control Logic Function



a. 0 V to 2.56 V Output Range



b. 0 V to 10 V Output Range

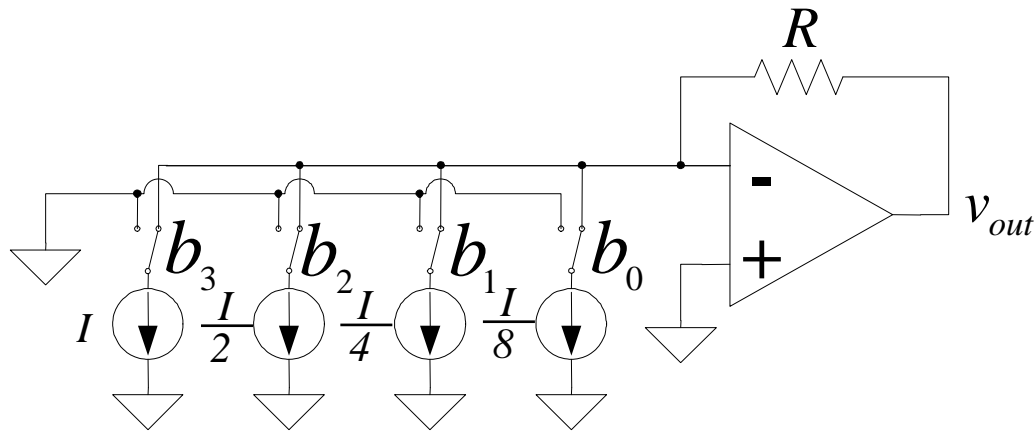
Very similar to a non-inverting amp

Strap output for different voltage ranges

Input Logic Coding

Digital Input Code			Output Voltage	
Binary	Hexadecimal	Decimal	2.56 V Range	10.000 V Range
0000 0000	00	0	0	0
0000 0001	01	1	0.010 V	0.039 V
0000 0010	02	2	0.020 V	0.078 V
0000 1111	0F	15	0.150 V	0.586 V
0001 0000	10	16	0.160 V	0.625 V
0111 1111	7F	127	1.270 V	4.961 V
1000 0000	80	128	1.280 V	5.000 V
1100 0000	C0	192	1.920 V	7.500 V
1111 1111	FF	255	2.55 V	9.961 V

Convert data to Offset binary

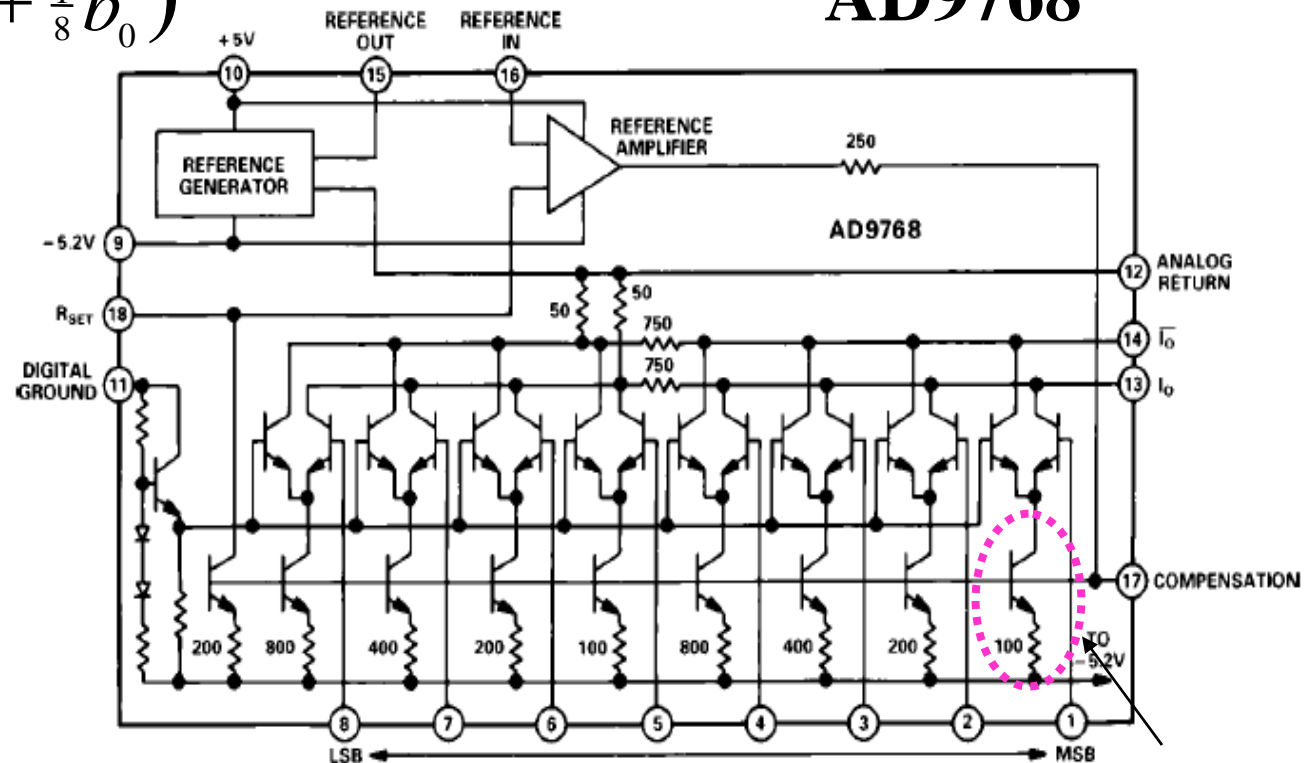


$$v_{out} = -IR \left(b_3 + \frac{1}{2}b_2 + \frac{1}{4}b_1 + \frac{1}{8}b_0 \right)$$

- Switch binary-weighted currents
- MSB to LSB current ratio is 2^N

- Analog Devices AD9768 uses two banks of ratioed currents
- Additional current division performed by 750Ω resistor between the two banks

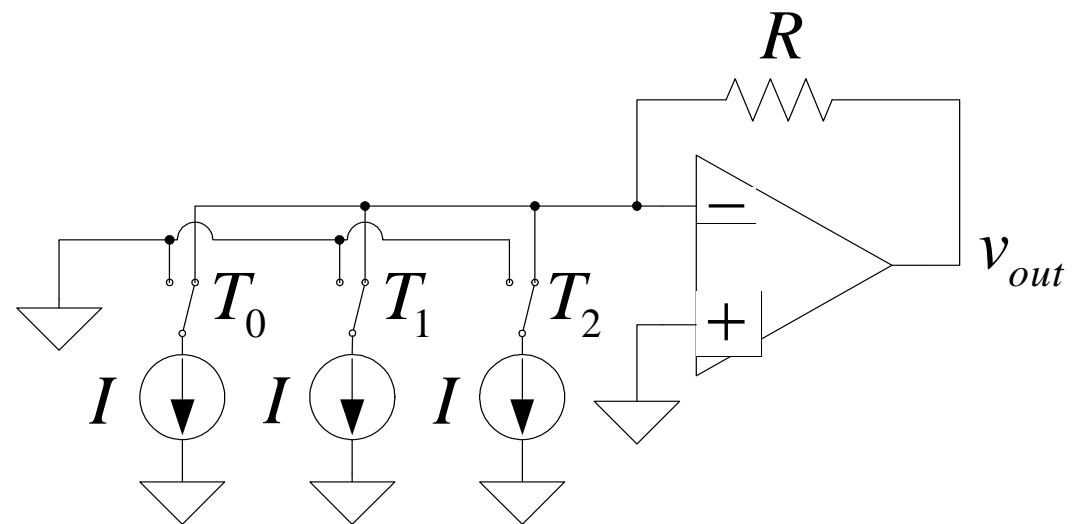
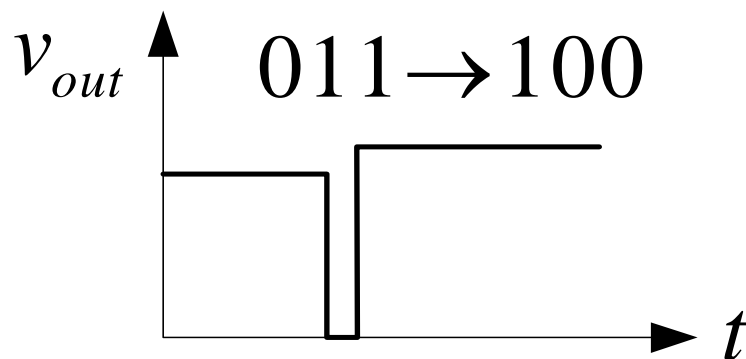
AD9768



Reference current source

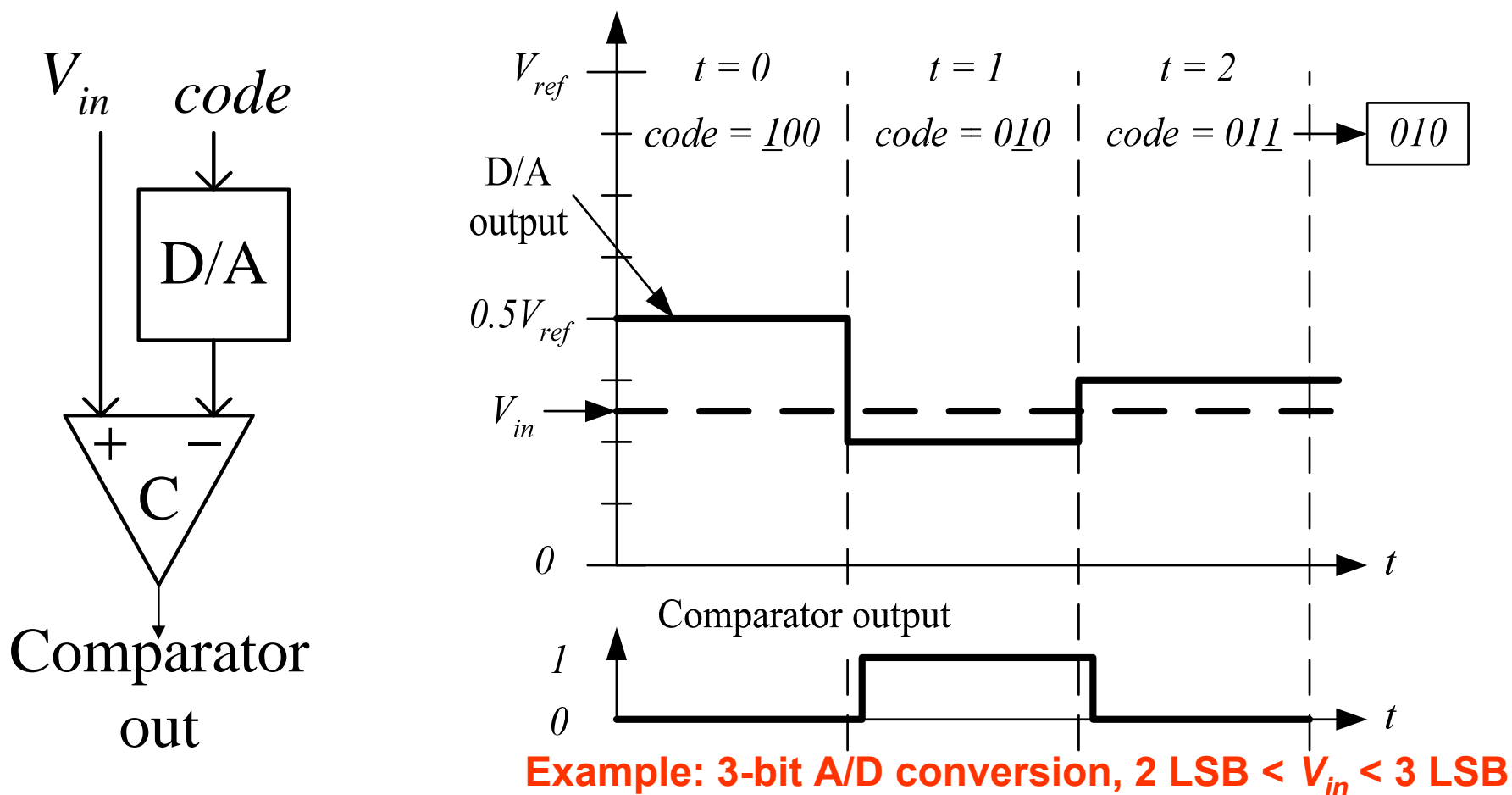
- Glitching is caused when switching times in a D/A are not synchronized
- Example: Output changes from 011 to 100 – MSB switch is delayed
- Filtering reduces glitch but increases the D/A settling time
- One solution is a thermometer code D/A – requires $2^N - 1$ switches but no ratioed currents

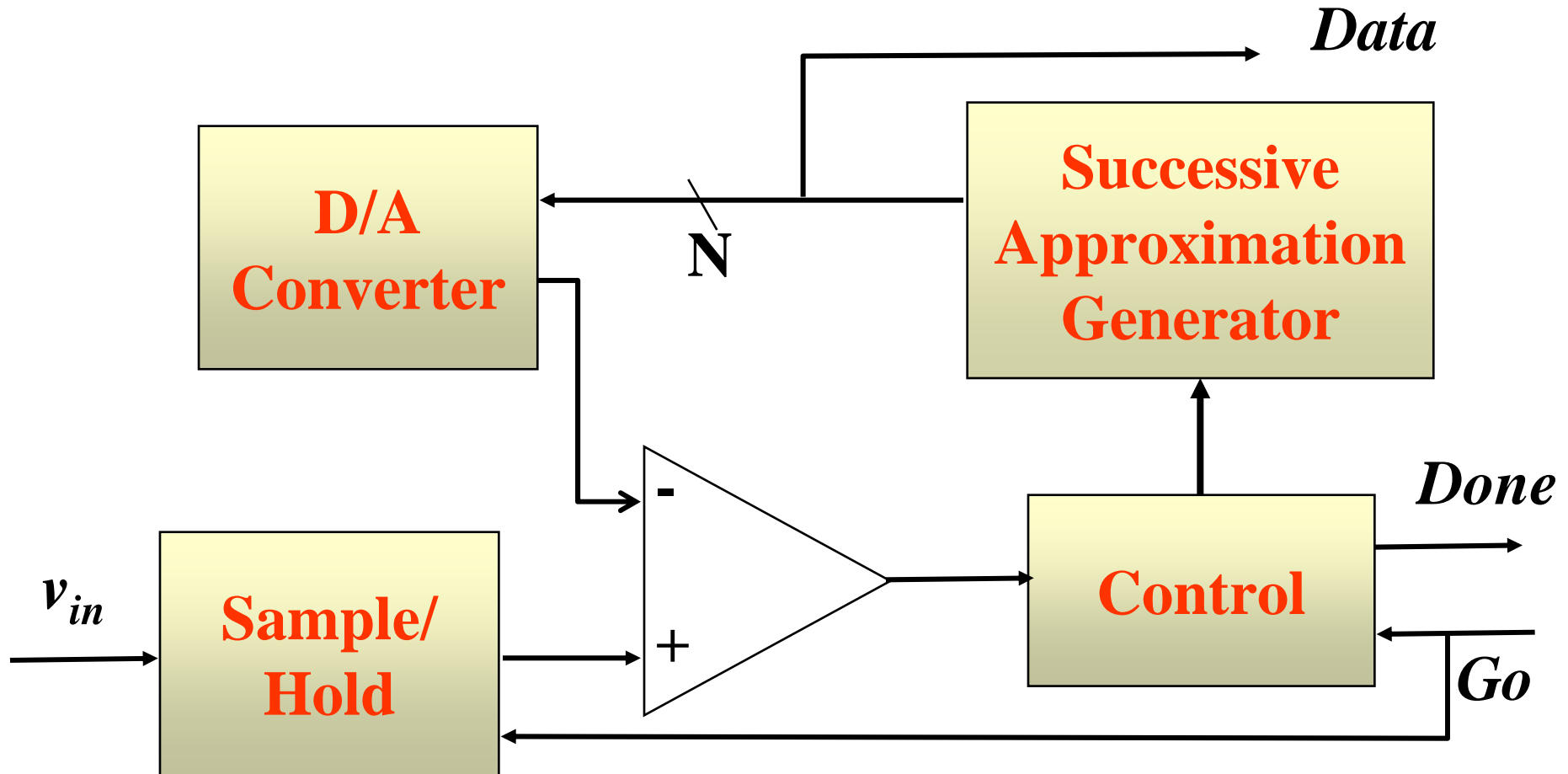
Binary		Thermometer		
0	0	0	0	0
0	1	0	0	1
1	0	0	1	1
1	1	1	1	1



$$v_{out} = -IR(T_0 + T_1 + T_2)$$

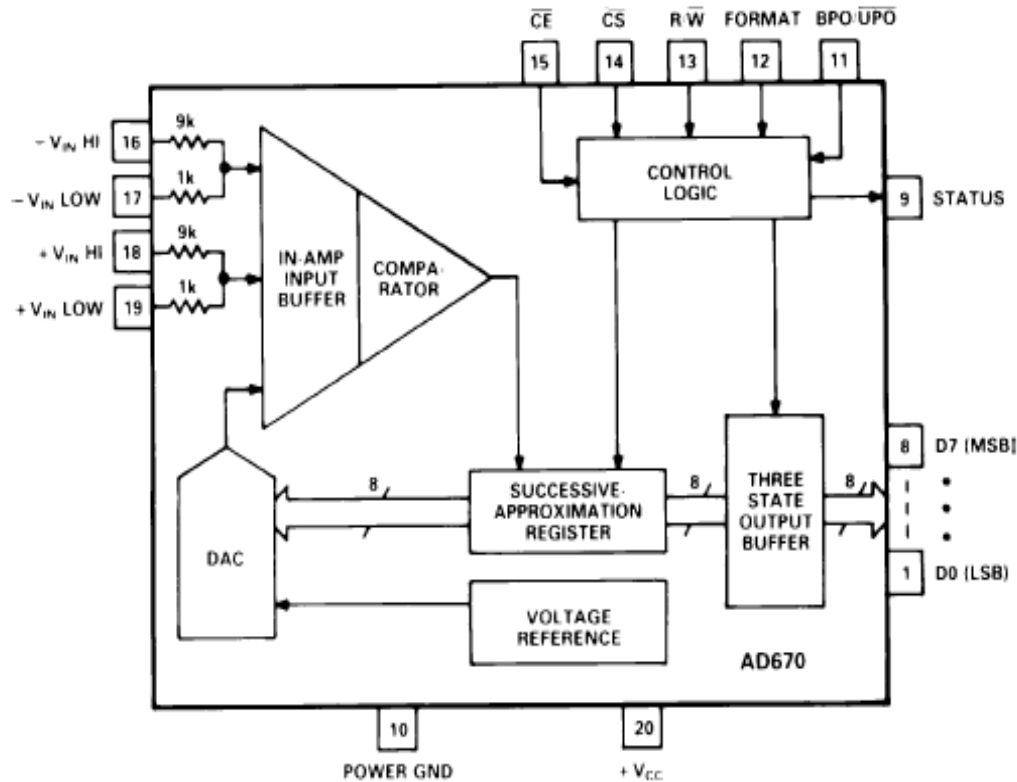
- **D/A converters are typically compact and easier to design. Why not A/D convert using a D/A converter and a comparator?**
- **D to A generates analog voltage which is compared to the input voltage**
- **If D to A voltage > input voltage then set that bit; otherwise, reset that bit**
- **This type of A to D takes a fixed amount of time proportional to the bit length**



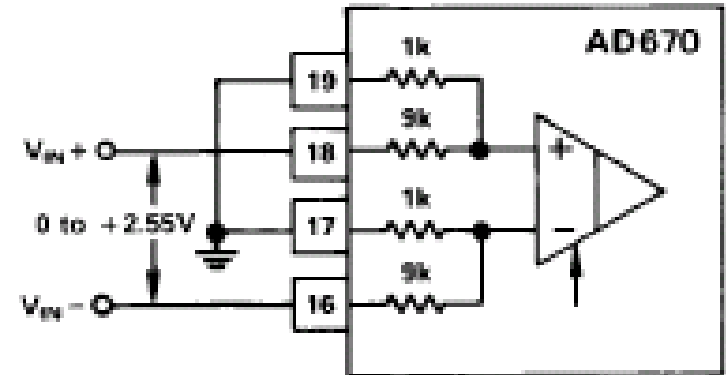


- Serial conversion takes a time equal to $N(t_{D/A} + t_{comp})$

Successive-Approximation A/D (AD670)

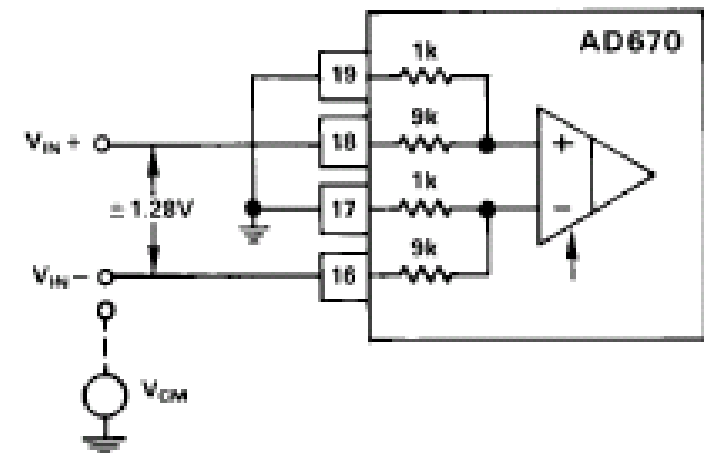


Unipolar (BPO = 0)



2a. 0 V to 2.55 V (10 mV/LSB)

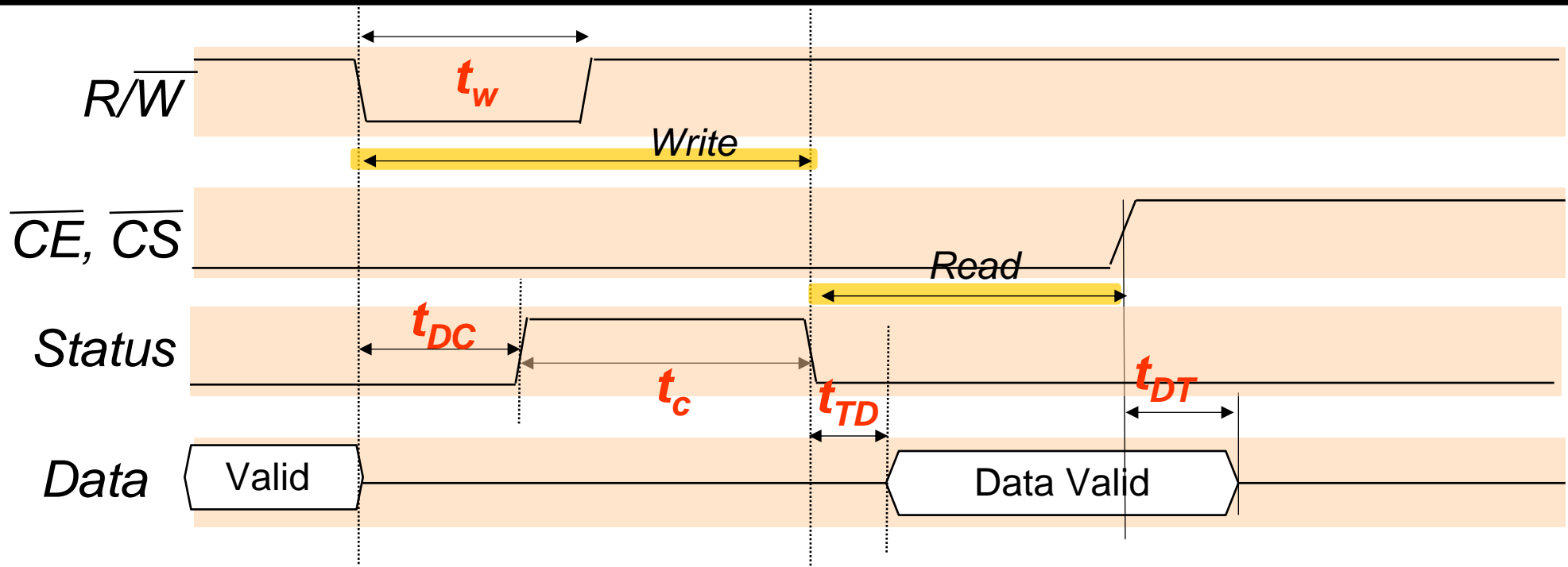
Bipolar (BPO = 1)



3a. ±1.28 V Range

BPO/ \overline{UPO}	FORMAT	INPUT RANGE/ OUTPUT FORMAT
0	0	Unipolar/Straight Binary
1	0	Bipolar/Offset Binary
0	1	Unipolar/2s Complement
1	1	Bipolar/2s Complement

Single Write, Single Read Operation (see data sheet for other modes)



t_w (write/start pulse width) = 300ns (min)

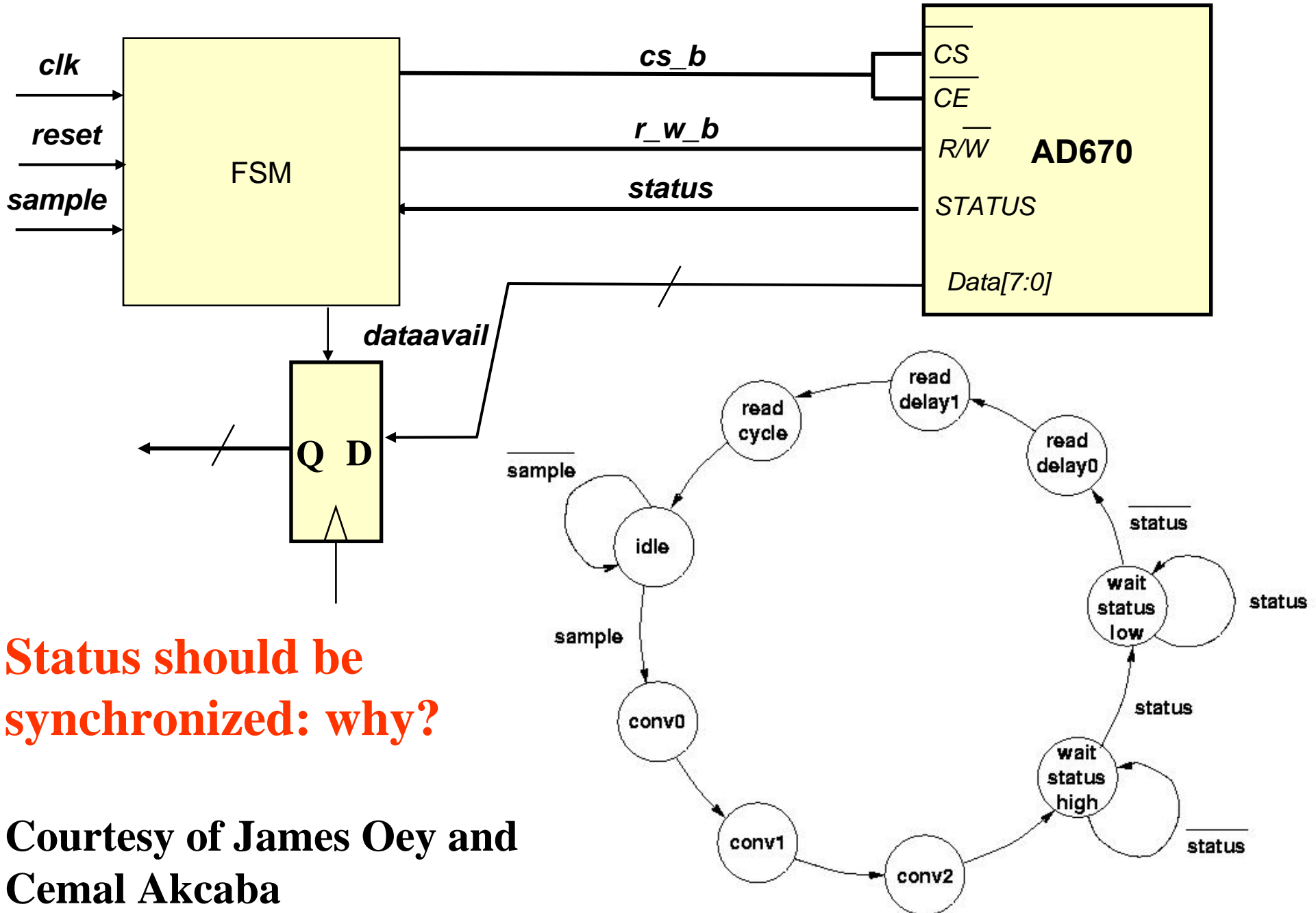
t_{DC} (delay to start conversion) = 700ns (max)

t_c (conversion time) = 10 μ s (max)

t_{TD} (Bus Access Time) = 250 (max)

t_{DT} (Output Float Delay) = 150 (max)

- Control bits \overline{CE} and \overline{CS} can be wired to ground if A/D is the only chip driving the bus
- Suggestion: tie \overline{CE} and \overline{CS} pins together and hardwire BPO and Format



Status should be synchronized: why?

Courtesy of James Oey and Cemal Akcaba

```

module AD670 (clk, reset, sample, dataavail,
  r_wbar, cs_bar, status, state);

  // System Clk
  input clk;
  // Global Reset signal, assume it is synchronized

  input reset;

  // User Interface
  input sample;
  output dataavail;

  // A-D Interface
  input status;
  reg status_d1, status_d2;
  output r_wbar, cs_bar;
  output [3:0] state;

  // internal state
  reg [3:0] state;
  reg [3:0] nextstate;
  reg r_wbar_int, r_wbar;
  reg cs_bar_int, cs_bar;
  reg dataavail;

```

1/5

```

  // State declarations.
  parameter IDLE = 0;
  parameter CONV0 = 1;
  parameter CONV1 = 2;
  parameter CONV2 = 3;
  parameter WAITSTATUSHIGH = 4;
  parameter WAITSTATUSLOW = 5;
  parameter READDELAY0 = 6;
  parameter READDELAY1 = 7;
  parameter READCYCLE = 8;

  always @ (posedge clk or negedge reset)
  begin
    if (!reset) state <=IDLE;
    else state <=nextstate;

    status_d1 <= status;
    status_d2 <= status_d1;

    r_wbar <= r_wbar_int;
    cs_bar <=cs_bar_int;

  end

```

2/5

```

always @ (state or status_d2 or sample) begin
  // defaults
  r_wbar_int = 1; cs_bar_int = 1; dataavail = 0;

  case (state)

    IDLE: begin
      if(sample) nextstate = CONV0;
      else nextstate = IDLE;
      end

    CONV0:
      begin
        r_wbar_int = 0;
        cs_bar_int = 0;
        nextstate = CONV1;
      end

    CONV1:
      begin
        r_wbar_int = 0;
        cs_bar_int = 0;
        nextstate = CONV2;
      end
  end

```

3/5

```

    CONV2:
      begin
        r_wbar_int = 0;
        cs_bar_int = 0;
        nextstate = WAITSTATUSHIGH;
      end

    WAITSTATUSHIGH:
      begin
        cs_bar_int = 0;
        if (status_d2) nextstate = WAITSTATUSLOW;

        else nextstate = WAITSTATUSHIGH;
      end

    WAITSTATUSLOW:
      begin
        cs_bar_int = 0;
        if (!status_d2) nextstate = READDELAY0;
        else nextstate = WAITSTATUSLOW;
      end
  end

```

4/5

```
    READDELAY0:
    begin
        cs_bar_int = 0;
        nextstate = READDELAY1;
    end

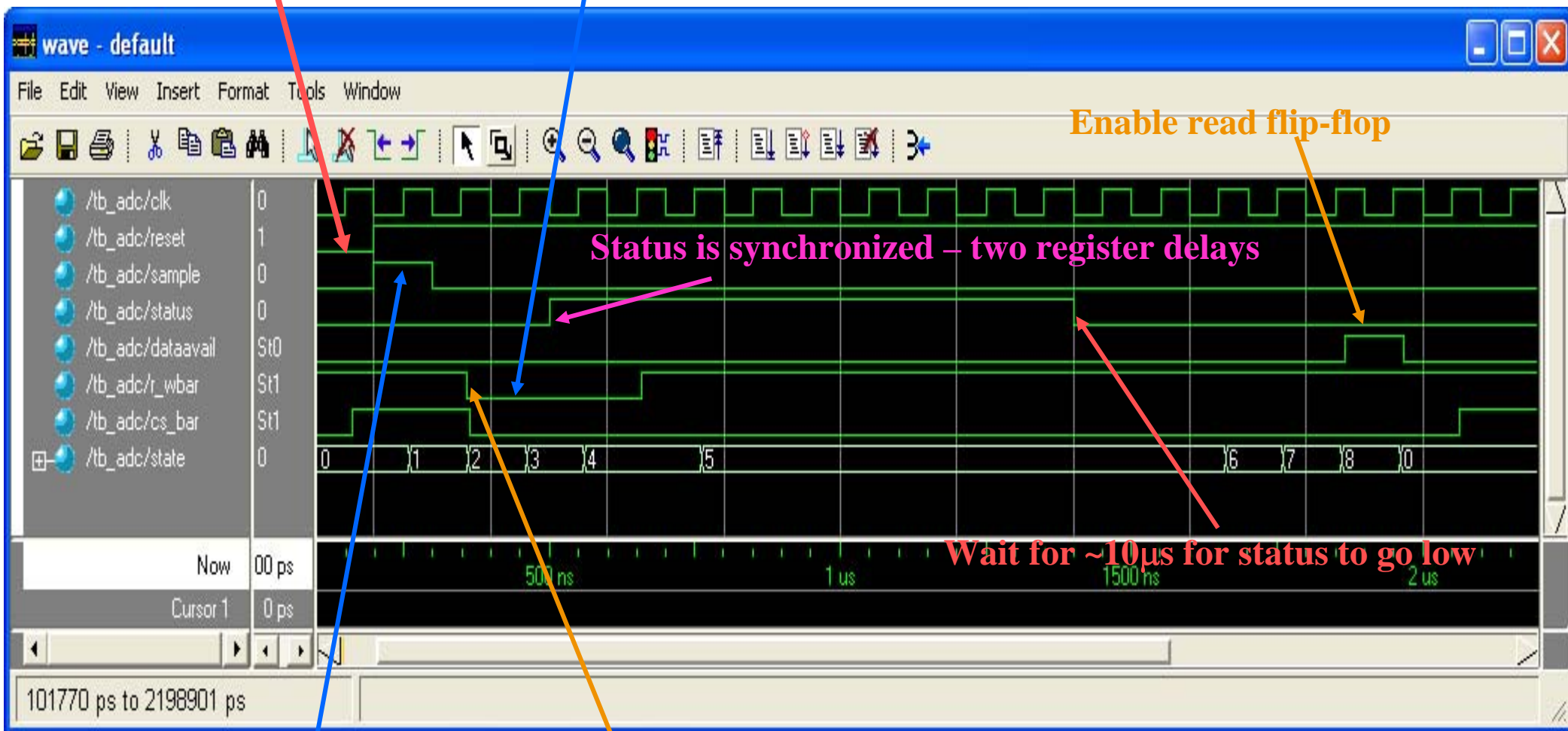
    READDELAY1:
    begin
        cs_bar_int = 0;
        nextstate = READCYCLE;
    end

    READCYCLE:
    begin
        cs_bar_int = 0;
        dataavail = 1;
        nextstate = IDLE;
    end

    default: nextstate = IDLE;
endcase // case(state)
end // always @ (state or status_d2 or sample)
endmodule // adcInterface
```

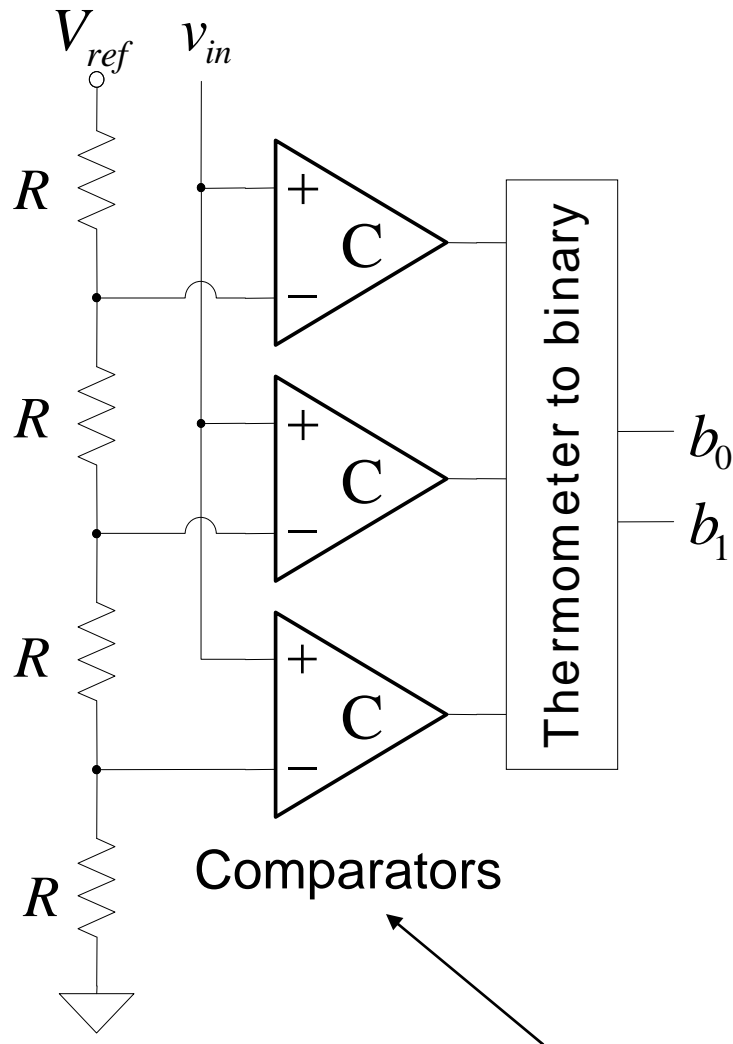
5/5

On reset, present state goes to 0 **r_w_b must stay low for at least 3 cycles (@ 100ns period)**



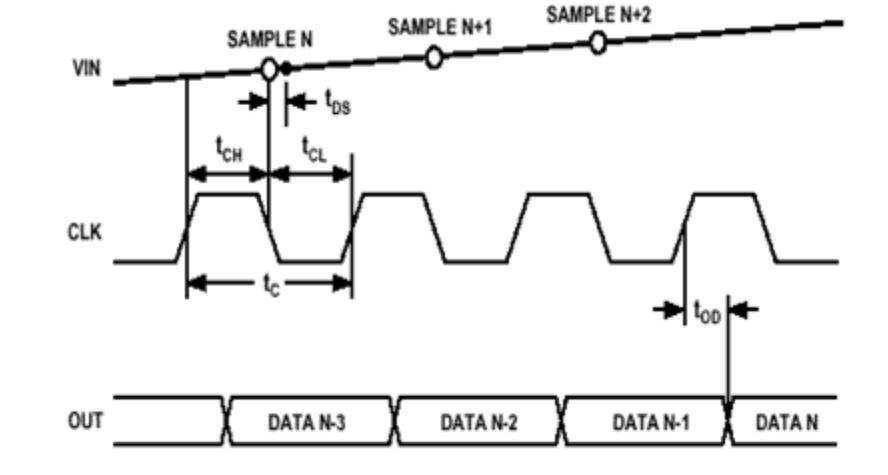
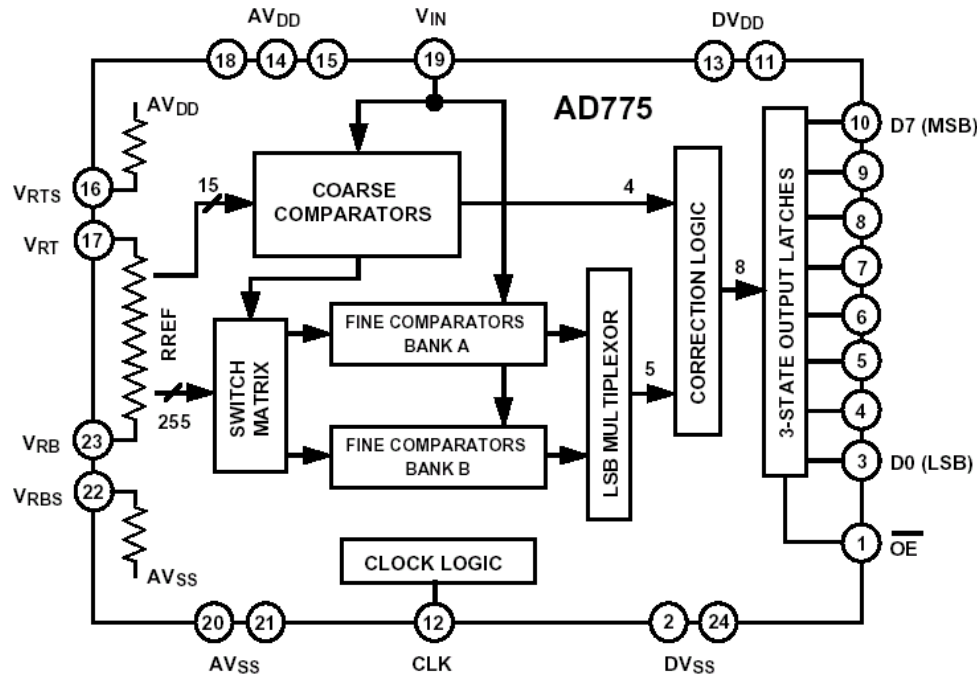
Sample pulse initiates data conversion

Notice a one cycle delay since A/D control signal delayed through a register



- Brute-force A/D conversion
- Simultaneously compare the analog value with every possible reference value
- Fastest method of A/D conversion
- **Size scales exponentially with precision**
(requires 2^N comparators)

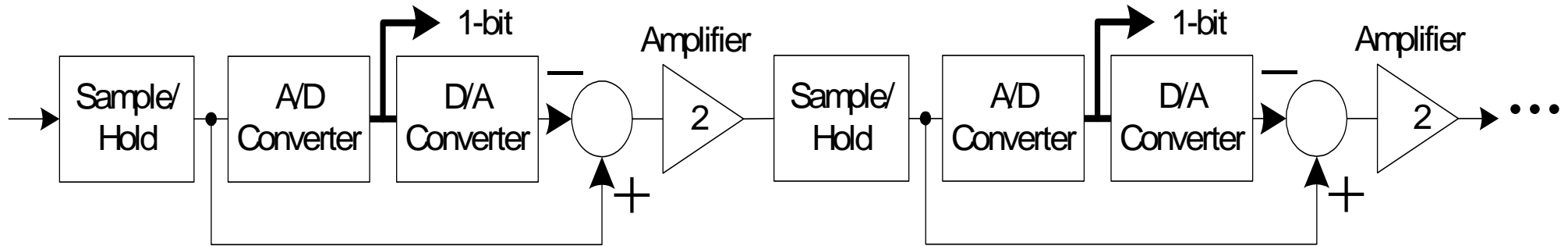
Can be implemented as OpAmp in open loop



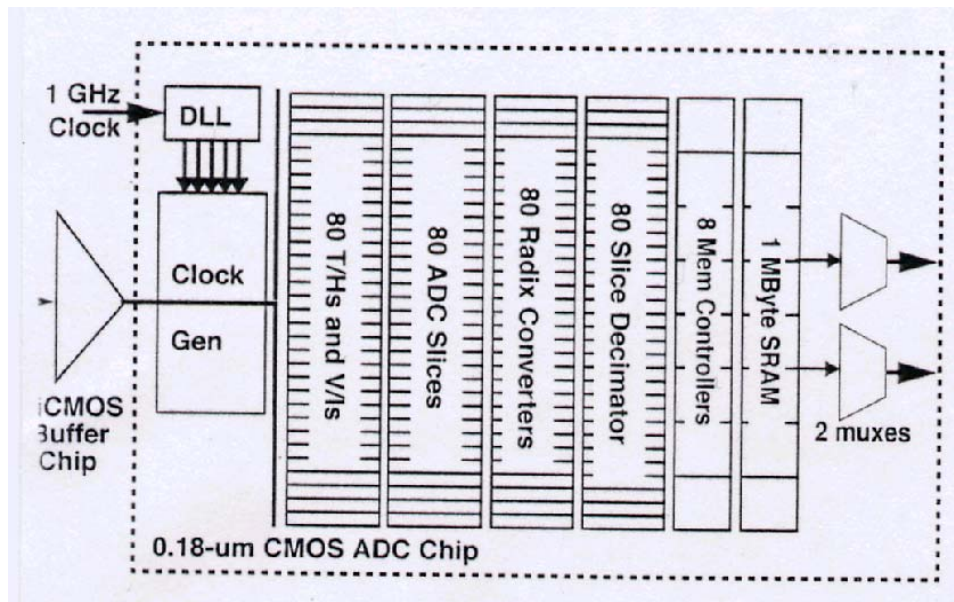
TIMING SPECIFICATIONS

	Symbol	Min	Typ	Max	Units
Maximum Conversion Rate		20	35		MHz
Clock Period	t_c	50			ns
Clock High	t_{CH}	25			ns
Clock Low	t_{CL}	25			ns
Output Delay	t_{OD}		18	30	ns
Pipeline Delay (Latency)				2.5	Clock Cycles
Sampling Delay	t_{DS}		4		ns
Aperture Jitter			30		ps

Pipelining (used in video rate, RF basestations, etc.)



Parallelism (use many slower A/D's in parallel to build very high speed A/D converters)



[ISSCC 2003],
Poulton et. al.

20Gsample/sec,
8-bit ADC
from Agilent Labs

- Analog blocks are integral components of any system. Need data converters (analog to digital and digital to analog), analog processing (OpAmps circuits, switched capacitors filters, etc.), power converters (e.g., DC-DC conversion), etc.
- We looked at example interfaces for A/D and D/A converters
 - Make sure you register critical signals (enables, R/\overline{W} , etc.)
- **Analog design incorporate digital principles**
 - Glitch free operation using coding
 - Parallelism and Pipelining!
 - More advanced concepts such as calibration